Ferrite Chip Bead(Lead Free)

FCM0603WF-121T04

		ECN HISTO	RY LIS	Γ	
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN
1.0	13/06/06	變更可靠度條件	楊祥忠	羅培君	張嘉玲
2.0	14/01/24	變更電鍍錫層厚度 3.0um min.=>3.5um min.	楊祥忠	羅培君	張嘉玲
3.0	14/08/01	變更 Reflow 圖示	楊祥忠	羅培君	張嘉玲
4.0	16/01/26	增訂可靠度 Thermal shock: (Bead) Step3:125±2℃ 30±5min	楊祥忠	詹偉特	張嘉玲
5.0	17/02/16	修訂 Recommended PC Board Pattern	楊祥忠	詹偉特	張嘉玲
備					
註					

TAI-TECH TBM01-191200248

Ferrite Chip Bead(Lead Free)

FCM0603WF-121T04

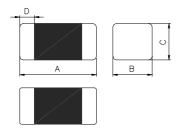
Certificate

Green Partner

1. Features

- 1. Monolithic inorganic material construction.
- 2. Closed magnetic circuit avoids crosstalk.
- 3. S.M.T. type.
- 4. Suitable for reflow soldering.
- 5. Shapes and dimensions follow E.I.A. spec.
- 6. Available in various sizes.
- 7. Excellent solder ability and heat resistance.
- 8. High reliability.
- 9. 100% Lead(Pb) & Halogen-Free and RoHS compliant.
- 10. Operating Temperature: -55~+125°C (Including self-temperature rise)

2. Dimensions



Chip Size					
Α	0.60±0.03				
В	0.30±0.03				
С	0.30±0.03				
D	0.15±0.05				

Units: mm

3. Part Numbering



A: Series

B: Dimension

C: Material

D: Impedance

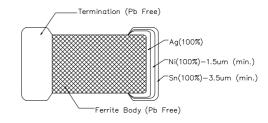
E: Packaging F: Rated Current

LxW

Lead Free Material

121=120 Ω

T=Taping and Reel, B=Bulk(Bags)



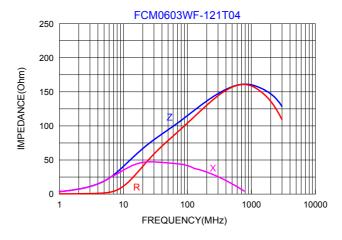
4. Specification

Tai-Tech Part Number	Impedance (Ω)	Test Frequency (Hz)	DC Resistance (Ω) max.	Rated Current (mA) max.
FCM0603WF-121T04	120±25%	60mV/100M	0.45	400

- Rated current: based on temperature rise test
- In compliance with EIA 595

Impedance-Frequency Characteristics

Ε



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 TAI-TECH
 TBM01-191200248
 P3

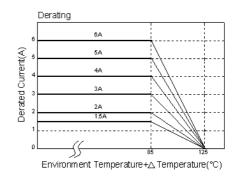
5. Reliability and Test Condition

Item		Performance				Tes	t Cond	lition			
Series No.	FCB FCM	HCB	GHB	FCA							
Operating Temperature	(Inc	-55∼+125℃ luding self-tempera	ture rise)								
Transportation Storage Temperature		-55~+125℃ (on board)			For long	_		ns, please	see the		
Impedance (Z)	Refer to standard electrical	obaractoristics list			Agilent42 Agilent E Agilent42 Agilent16	4991 287					
DC Resistance	Refer to standard electrical	characteristics list			Agilent 43						
Rated Current									re will be		
Temperature Rise Test	Rated Current < 1A ΔT 20 $^{\circ}$ C Ma Rated Current \geq 1A ΔT 40 $^{\circ}$ C Ma			2. Tempe thermo	rature m ometer.		by digital su				
Life test	Appearance: no damage.								v for 2 sification		
Load Humidity	Q : Shall not exceed the sp	Inductance: within±10% of initial value. Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value						Preconditioning: Run through IR reflow for 2 times. (IPC/JEDEC J-STD-020D Classification Reflow Profiles) Humidity: 85±2%R.H. Temperature: 85±2°C. Duration: 1000hrs Min. with 100% rated current. Measured at room temperature after placing for 24±2 hrs.			
Thermal shock	Appearance: no damage. Impedance: within±15%of initial value. Inductance: within±10%of initial value. Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value.					Preconditioning: Run through IR reflow for 2 times. (IPC/JEDEC J-STD-020D Classification Reflow Profiles) Condition for 1 cycle Step1: -55±2°C 30±5 min. Step2: 25±2°C ≤ 0.5min Step3: +125±2°C 30±5min. Number of cycles: 500 Measured at room temperature after placing for 24±2 hrs.					
Vibration	Appearance : No damage. Impedance : within±15% or Inductance : within±10% of Q : Shall not exceed the sp RDC : within ±15% of initia	initial value ecification value.	t exceed the spe	ecification value	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classificatio Reflow Profiles) Oscillation Frequency: 10Hz~2KHz~10Hz for 20 minutes Equipment: Vibration checker Total Amplitude:10g Testing Time: 12 hours(20 minutes, 12 cycles each of 3 orientations)			sification 10Hz			
Bending	Appearance: No damage. Impedance: within±10% or Inductance: within±10% of Q: Shall not exceed the sp. RDC: within ±15% of initial	initial value ecification value.	t exceed the spe	ecification value	Shall be mounted on a FR4 substrate of the following dimensions: >=0805inch(2012mm):40x100x1.2mm <0805inch(2012mm):40x100x0.8mm Bending depth: >=0805inch(2012mm):1.2mm <0805inch(2012mm):0.8mm Duration of 10 sec for a min.						
	Appearance (NI) days				Test cor		Name		into all		
Shock	Appearance : No damage. Impedance : within±10% of Inductance : within±10% of	initial value			Туре	Peak Value (g's)	Normal duration (D) (ms)	Wave form	iplocity change (Vi)ft/sec		
	Q : Shall not exceed the sp RDC : within ±15% of initia		t exceed the spe	ecification value	SMD	50	11	Half-sine	11.3		
	. 5,5 5. 2. 2.				Lead	50	11	Half-sine	11.3		
Solderability	More than 95% of the termin	nal electrode should	be covered with	n solder.	Preheat: Solder: S Solder te Flux for le Depth: co Dip time:	in96.5% mperatu ead free: ompletel	-Ag3%-Cure: 245±5 Rosin. 9 y cover th	i°C	on.		

Item	Performance	Test Condition		
		Number of heat cycles: 1		
Resistance to Soldering	Appearance : No damage. Impedance : within±15% of initial value	Temperature (°C) Time (s) Temperature ramp/immersion and emersion rate		
Heat	Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value	260 ±5 (solder temp) 10 ±1 25mm/s ±6 mm/s		
		Depth: completely cover the termination		
Terminal strength	Appearance : No damage. Impedance : within±15% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for times.(IPC/JEDEC J-STD-020D Classificat Reflow Profiles) Component mounted on a PCB apply a for >0805inch(2012mm):1kg <=0805inch(2012mm):0.5kg to the side of a device being tested. This for shall be applied for 60 +1 seconds. Also to force shall be applied gradually as not to shot the component being tested.		

**Derating Curve

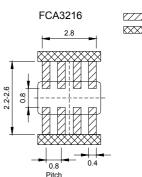
For the ferrite chip bead which withstanding current over 1.5A, as the operating temperature over $85^{\circ}\mathrm{C}$, the derating current information is necessary to consider with. For the detail derating of current, please refer to the Derated Current vs. Operating Temperature curve.



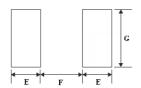
6. Soldering and Mounting

6-1. Recommended PC Board Pattern

	Chip Size							Land Patterns For Reflow Soldering		
Series	Type A(mm)		B(mm)	C(mm)	D(mm)	E(mm)	F(mm)	G(mm)		
	<mark>0603</mark>	0.6±0.03	0.30±0.03	0.30±0.03	0.15±0.05	<mark>0.35</mark>	<mark>0.30</mark>	<mark>0.40</mark>		
FCB	1005	1.0±0.10	0.50±0.10	0.50±0.10	0.25±0.10	0.50	0.40	0.60		
FCM	1608	1.6±0.15	0.80±0.15	0.80±0.15	0.30±0.20	0.80	0.85	0.95		
HCB		2.0±0.20	1.25±0.20	0.85±0.20	0.50±0.30					
GHB	2012	2.0±0.20	1.25±0.20	1.25±0.20	0.50±0.30	1.05	1.00	1.45		
FCI	3216	3.2±0.20	1.60±0.20	1.10±0.20	0.50±0.30	1.05	2.20	1.80		
FHI	3225	3.2±0.20	2.50±0.20	1.30±0.20	0.50±0.30	1.05	2.20	2.70		
FCH	4516	4.5±0.20	1.60±0.20	1.60±0.20	0.50±0.30	1.05	3.30	1.80		
HCI	4532	4.5±0.20	3.20±0.20	1.50±0.20	0.50±0.30	1.05	3.30	3.40		



Land
Solder Resist



PC board should be designed so that products can prevent damage from mechanical stress when warping the board.

TAI-TECH **TBM01-191200248** P5

6-2. Soldering

Mildly activated rosin fluxes are preferred. The terminations are suitable for re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools. Note

If wave soldering is used ,there will be some risk.

Re-flow soldering temperatures below 240 degrees, there will be non-wetting risk

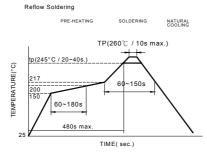
6-2.1 Lead Free Solder re-flow:

Recommended temperature profiles for lead free re-flow soldering in Figure 1. (Refered to J-STD-020C)

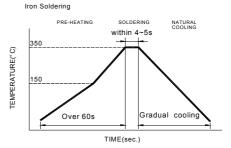
6-2.2 Soldering Iron:

Products attachment with a soldering iron is discouraged due to the inherent process control limitations. If a soldering iron must be employed the following precautions are recommended. for Iron Soldering in Figure 2.

- Preheat circuit and products to 150°C • 350°C tip temperature (max)
- · Never contact the ceramic with the iron tip • 1.0mm tip diameter (max)
- Use a 20 watt soldering iron with tip diameter of 1.0mm
 - · Limit soldering time to 4~5sec.



Reflow times: 3 times max Fig.1



Iron Soldering times: 1 times max Fig.2

6-2.3 Solder Volume:

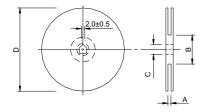
Accordingly increasing the solder volume, the mechanical stress to product is also increased. Exceeding solder volume may cause the failure of mechanical or electrical performance. Solder shall be used not to be exceed as shown in right side:

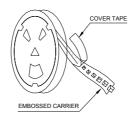
Minimum fillet height = soldering thickness + 25% product height



7. Packaging Information

7-1. Reel Dimension

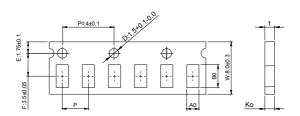




Туре	A(mm)	B(mm)	C(mm)	D(mm)	
7"x8mm	10±1.5	50 or more	13±0.2	178±2	

7-2. Tape Dimension / 8mm

■Material of taping is paper



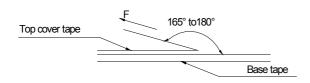
Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	t(mm)
060303	0.70±0.06	0.40±0.06	0.45max	2.0±0.05	0.45max

TAI-TECH TBM01-191200248 P6

7-3. Packaging Quantity

Chip Size	060303
Chip / Reel	15000
Inner box	75000
Middle box	375000
Carton	750000

7-4. Tearing Off Force



The force for tearing off cover tape is 15 to 60 grams in the arrow direction under the following conditions.

Room Temp.	Room Humidity	Room atm	Tearing Speed
(℃)	(%)	(hPa)	mm/min
5~35	45~85	860~1060	300

Application Notice

· Storage Conditions(component level)

To maintain the solder ability of terminal electrodes:

- 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 3. Recommended products should be used within 12 months from the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
- 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
- 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
- 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.



Test Report

號碼(No.): CE/2019/C0498 日期(Date): 2019/12/10 頁數(Page): 1 of 14

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO., LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA) (中國,江蘇省,宿遷市,泗洪縣,經濟開發區杭州路南側,建設北路東側 / THE SOUTH HANGZHOU ROAD AND THE EAST JIANSHE ROAD, ECONOMIC DEVELOPMENT ZONE, SIHONG COUNTY, SUQIANCITY, JIANGSU PROVINCE, P, R, CHINA)

以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as):

樣品名稱(Sample Description)

FERRITE CHIP BEAD · FERRITE CHIP INDUCTOR · ARRAY · MCF · MCM · YMV · APM SERIES

樣品型號(Style/Item No.)

FERRITE CHIP BEAD · FERRITE CHIP INDUCTOR · ARRAY · MCF · MCM · YMV · APM SERIES

收件日期(Sample Receiving Date)

2019/12/04

測試期間(Testing Period)

2019/12/04 to 2019/12/10

測試結果(Test Results) : 請參閱下一頁 (Please refer to following pages).

Troy Chang / Manager - Te Signed for and behalf of SĞS TAIWAN LTD.

Chemical Laboratory - Taipei

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Test Report

號碼(No.): CE/2019/C0498

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頁數(Page): 2 of 14

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測試結果(Test Results)

測試部位(PART NAME)No.1

: 整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	测試方法 (Method)	MDL	結果 (Result) No.1
鎬 / Cadmium (Cd)	mg/kg	參考IEC 62321-5 (2013),以感應耦合電 漿發射光譜儀檢測. / With reference	2	n. d.
鉛 / Lead (Pb)	mg/kg	to IEC 62321-5 (2013) and performed by ICP-OES.	2	n. d.
汞 / Mercury (Hg)	mg/kg	参考IEC 62321-4:2013+ AMD1:2017,以 感應耦合電漿發射光譜儀檢測. / With reference to IEC 62321-4:2013+ AMD1:2017 and performed by ICP-OES.	2	n. d.
六價络 / Hexavalent Chromium Cr(VI)	mg/kg	参考IEC 62321-7-2 (2017),以UV-VIS檢 測. / With reference to IEC 62321-7- 2 (2017) and performed by UV-VIS.	8	n. d.
多溴聯苯總和 / Sum of PBBs	mg/kg		_	n. d.
一溴聯苯 / Monobromobiphenyl	mg/kg]	5	n. d.
二溴聯苯 / Dibromobiphenyl	mg/kg	Ι Γ	5	n, d,
三溴聯苯 / Tribromobiphenyl	mg/kg	h.xna anand a (and a)	5	n, d,
四溴聯苯 / Tetrabromobiphenyl	mg/kg	參考IEC 62321-6 (2015),以氣相層析/	5	n, d,
五溴聯苯 / Pentabromobiphenyl	mg/kg	質譜儀檢測. / With reference to IEC - 62321-6 (2015) and performed by	5	n. d.
六溴聯苯 / Hexabromobiphenyl	mg/kg	GC/MS.	5	n. d.
七溴聯苯 / Heptabromobiphenyl	mg/kg	OO/ MO.	5	n. d.
八溴聯苯 / Octabromobiphenyl	mg/kg]	5	n. d.
九溴聯苯 / Nonabromobiphenyl	mg/kg]	5	n. d.
十溴聯苯 / Decabromobiphenyl	mg/kg		5	n. d.

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頁數(Page): 3 of 14

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測試項目 (Test Items)	單位 (Unit)	测試方法 (Method)	MDL	結果 (Result) No.1
多溴聯苯醚總和 / Sum of PBDEs	mg/kg		_	n. d.
一溴聯苯醚 / Monobromodiphenyl ether	mg/kg		5	n. d.
二溴聯苯醚 / Dibromodiphenyl ether	mg/kg		5	n. d.
三溴聯苯醚 / Tribromodiphenyl ether	mg/kg	6 M TDO 00001 0 (0015)	5	n. d.
四溴聯苯醚 / Tetrabromodiphenyl ether	mg/kg	參考IEC 62321-6 (2015),以氣相層析/	5	n. d.
五溴聯苯醚 / Pentabromodiphenyl ether	mg/kg	質譜儀檢測./ With reference to IEC 62321-6 (2015) and performed by	5	n. d.
六溴聯苯醚 / Hexabromodiphenyl ether	mg/kg	GC/MS.	5	n, d.
七溴聯苯醚 / Heptabromodiphenyl ether	mg/kg	OO MO.	5	n. d.
八溴聯苯醚 / Octabromodiphenyl ether	ng/kg		5	n. d.
九溴聯苯醚 / Nonabromodiphenyl ether	mg/kg		5	n. d.
十溴聯苯醚 / Decabromodiphenyl ether	mg/kg		5	n. d.
六溴環十二烷及所有主要被辨別出的異構物 / Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified (α - HBCDD, β - HBCDD, γ - HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8))	mg/kg	參考IEC 62321 (2008),以氣相層析/質 譜儀檢測. / With reference to IEC 62321 (2008). Analysis was performed by GC/MS.	5	n. d.
鹵素 / Halogen				
鹵素 (氣) / Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg		50	n. d.
鹵素(氣)/ Halogen-Chlorine (C1) (CAS No.: 22537-15-1)	mg/kg	参考BS EN 14582 (2016),以離子層析儀 分析. / With reference to BS EN	50	n. d.
鹵素(溴)/ Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg	14582 (2016). Analysis was performed by IC.	50	n. d.
鹵素(碘)/ Halogen-Iodine(I)(CAS No.: 14362-44-8)	mg/kg		50	n. d.

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Test Report

號碼(No.): CE/2019/C0498

日期(Date): 2019/12/10

頁數(Page): 4 of 14

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	MDL	結果 (Result) No.1
鄰苯二甲酸丁苯甲酯 / BBP (Butyl Benzyl phthalate) (CAS No.: 85-68-7)	mg/kg	參考IEC 62321-8 (2017),以氣相層析/ 質譜儀檢測. / With reference to IEC 62321-8 (2017). Analysis was performed by GC/MS.	50	n. d.
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No.: 84-74-2)	mg/kg		50	n. d.
鄭苯二甲酸二 (2-乙基己基)酯 / DEHP (Di- (2-ethylhexyl) phthalate) (CAS No.: 117-81-7)	mg/kg		50	n. d.
鄰苯二甲酸二異丁酯 / DIBP (Di-isobutyl phthalate) (CAS No.: 84-69-5)	mg/kg		50	n. d.
鄰苯二甲酸二異癸酯 / DIDP (Di- isodecyl phthalate) (CAS No.: 26761- 40-0; 68515-49-1)	mg/kg		50	n. d.
鄉苯二甲酸二異壬酯 / DINP (Di- isononyl phthalate) (CAS No.: 28553- 12-0; 68515-48-0)	mg/kg		50	n. d.
鄰苯二甲酸二正辛酯 / DNOP (Di-n-octyl phthalate) (CAS No.: 117-84-0)	mg/kg		50	n. d.
鄰苯二甲酸二正己酯 / DNHP (Di-n-hexyl phthalate) (CAS No.: 84-75-3)	mg/kg		50	n. d.
鄰苯二甲酸二戊酯 / DNPP (Di-n-pentyl phthalate) (CAS No.: 131-18-0)	mg/kg		50	n. d.
全氟辛烷磺酸 / Perfluorooctane sulfonates (PFOS-Acid, Metal Salt, Amide)	mg/kg	参考US EPA 3550C (2007),以液相層析/ 質譜儀檢測. / With reference to US EPA 3550C (2007). Analysis was	10	n. d.
全氟辛酸 / PFOA (CAS No.: 335-67-1)	mg/kg	performed by LC/MS.	10	n. d.

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Test Report

號碼(No.): CE/2019/C0498

日期(Date): 2019/12/10

頁數(Page): 5 of 14

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	MDL	結果 (Result) No.1
銻 / Antimony (Sb)	mg/kg	参考US EPA 3052 (1996),以感應耦合電	2	n. d.
鈹 / Beryllium (Be)	mg/kg	漿發射光譜儀檢測. / With reference to US EPA 3052 (1996). Analysis was	2	n. d.
砷 / Arsenic (As)	mg/kg	performed by ICP-OES.	2	n, d,
聚氯乙烯 / Polyvinyl chloride (PVC)	**	以紅外光譜分析及焰色法檢測. / Analysis was performed by FTIR and FLAME Test.	_	Negative

備註(Note):

- 1. mg/kg = ppm : 0.1wt% = 1000ppm
- 2. MDL = Method Detection Limit (方法偵測極限值)
- 3. n.d. = Not Detected (未檢出)
- 4. "-" = Not Regulated (無規格值)
- 5. **= Qualitative analysis (No Unit) 定性分析(無單位)
- 6. Negative = Undetectable 陰性(未偵測到); Positive = Detectable 陽性(已偵測到)
- 7. 樣品的測試是基於申請人要求混合測試,報告中的混合測試結果不代表其中個別單一材質的含量. (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

PFOS参考資訊(Reference Information): 持久性有機污染物 POPs - (EU) 2019/1021

PFOS濃度在物質或製備中不得超過0,001%(10ppm),在半成品、成品或零部件中不得超過0.1%(1000ppm),在紡織品或 塗層材料中不得超過1μg/m²。

(Outlawing PFOS as substances or preparations in concentrations above 0.001% (10ppm), in semi-finished products or articles or parts at a level above 0.1%(1000ppm), in textiles or other coated materials above lug/m².)

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Test Report

號碼(No.): CE/2019/C0498 日期(Date): 2019/12/10

頁數(Page): 6 of 14

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

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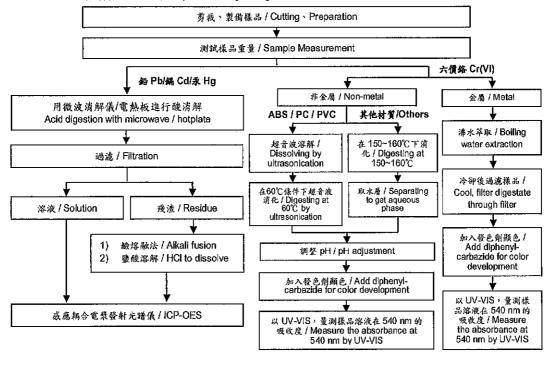
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重金屬流程圈 / Analytical flow chart of Heavy Metal

根據以下的流程圖之條件,樣品已完全溶解。 (六價鉻測試方法除外)

These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr8+ test method excluded)

- 測試人員:陳思臻 / Technician : Rita Chen
- 測試負責人:張啟興 / Supervisor: Troy Chang



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Test Report

號碼(No.): CE/2019/C0498 日期(Date): 2019/12/10 頁數(Page): 7 of 14

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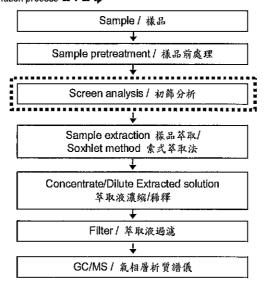
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多溴聯苯/多溴聯苯醚分析流程圖 / Analytical flow chart - PBB/PBDE

- 測試人員:涂雅苓 / Technician: Yaling Tu
- 測試負責人:張啟興 / Supervisor: Troy Chang

初次测试程序 / First testing process -確認程序 / Confirmation process - - - →



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Test Report

號碼(No.): CE/2019/C0498

日期(Date): 2019/12/10

頁數(Page): 8 of 14

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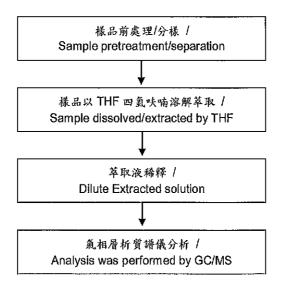
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可塑劑分析流程圖 / Analytical flow chart - Phthalate

測試人員:涂雅苓 / Technician: Yaling Tu

測試負責人:張啟興 / Supervisor: Troy Chang

【测試方法/Test method: IEC 62321-8】



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Test Report

號碼(No.): CE/2019/C0498

日期(Date): 2019/12/10

頁数(Page): 9 of 14

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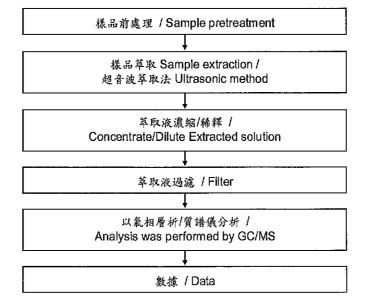
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六溴環十二烷分析流程圖 / Analytical flow chart - HBCDD

- 測試人員:涂雅苓 / Technician: Yaling Tu
- 測試負責人:張啟與 / Supervisor: Troy Chang



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Test Report

號碼(No.): CE/2019/C0498 日期(Date): 2019/12/10

頁數(Page): 10 of 14

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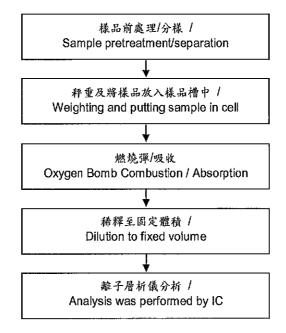
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鹵素分析流程圖 / Analytical flow chart - Halogen

- 測試人員:陳恩臻 / Technician: Rita Chen
- 測試負責人:張啟與 / Supervisor: Troy Chang



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Test Report

號碼(No.): CE/2019/C0498 日期(Date): 2019/12/10 頁數(Page): 11 of 14

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

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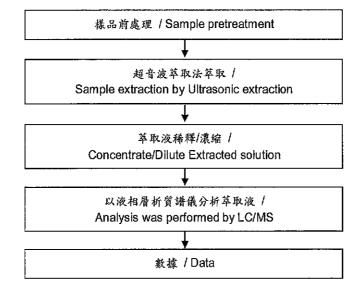
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全氟辛酸/全氟辛烷磺酸分析流程圖 / Analytical flow chart - PFOA/PFOS

- 測試人員:涂雅苓 / Technician: Yaling Tu
- 測試負責人:張啟興 / Supervisor: Troy Chang



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Test Report

號碼(No.): CE/2019/C0498

日期(Date): 2019/12/10

頁數(Page): 12 of 14

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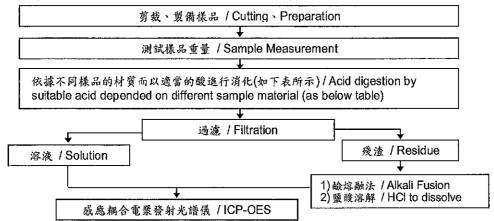
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> 根據以下的流程圖之條件,樣品已完全溶解。 / These samples were dissolved totally by pre-conditioning method according to below flow chart.

- 測試入員:陳恩臻 / Technician: Rita Chen
- 測試負責人:張啟興 / Supervisor: Troy Chang

元素以 ICP-OES 分析的消化流程圈 (Flow Chart of digestion for the elements analysis performed by ICP-OES)



鋼,銅,鋁,焊錫 / Steel, copper, aluminum, solder	王水,硝酸,鹽酸,氫氟酸,雙氧水 / Aqua regia, HNO ₃ , HCI, HF, H ₂ O ₂
玻璃 / Glass	硝酸,氫氟酸 / HNO3/HF
金,鉑,鈀,陶瓷 / Gold, platinum, palladium, ceramic	王水 / Aqua regia
銀 / Silver	硝酸 / HNO3
塑膠 / Plastic	硫酸,雙氧水,硝酸,鹽酸 / H2SO4, H2O2, HNO3, HCI
其他 / Others	加入適當的試劑至完全溶解 / Added appropriate reagent to total digestion

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Test Report

號碼(No.): CE/2019/C0498

日期(Date): 2019/12/10

頁數(Page): 13 of 14

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO., LTD.)

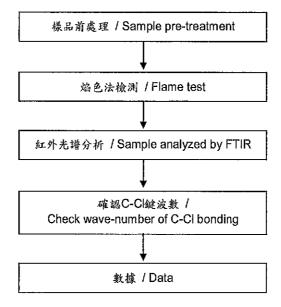
(慶邦電子元器件 (泗洪) 有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA) (中國,江蘇省,宿遷市,泗洪縣,經濟開發區杭州路南側,建設北路東側 / THE SOUTH HANGZHOU ROAD AND THE EAST JIANSHE ROAD, ECONOMIC DEVELOPMENT ZONE, SIHONG COUNTY, SUQIANCITY, JIANGSU PROVINCE, P, R, CHINA)

聚氯乙烯物質判定分析流程圖 / Analysis flow chart - PVC

- 測試人員:涂雅苓 / Technician: Yaling Tu
- 測試負責人:張啟興 / Supervisor: Troy Chang



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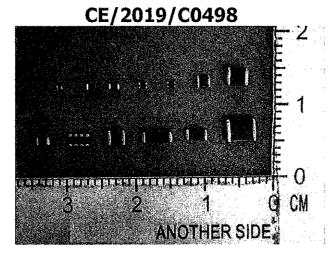
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* 照片中如有箭頭標示,則表示為實際檢測之樣品/部位. *

(The tested sample / part is marked by an arrow if it's shown on the photo.)

CE/2019/C0498



** 報告結尾 (End of Report) **

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